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PATENT APPLICATION
Docket No.:BGJ-102
Confirmation No. 1586

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Georg Muller

Application No.: 10/663,448 Group Art Unit: 2829

Filed: 9/16/2003 Examiner: Emily Y Chan

For: Semiconductor Device Testing Apparatus, Semiconductor Device Testing System, And Semiconductor Device Testing Method For Measuring And Trimming The Output Impedance Of Driver Devices

CERTIFICATE OF MAILING	
I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as First Class Mail in an envelope addressed to Mail Stop Amendment, Commissioner for Patents, Alexandria, VA 22313-1450	
on <u>January 13, 2005</u>	<u>Jacqueline M. Arendt</u> Signature
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REPLY TO RESTRICTION REQUIREMENT

Mail Stop Amendment
Commissioner for Patents
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Sir:

This Reply is submitted in response to the Office Action mailed from the Patent and Trademark Office on December 13, 2004.